

The logo for PE SYSTEMS features the text "PE SYSTEMS" in a dark blue, sans-serif font. The letters "P" and "E" are separated by a red dot, and the "S" and "Y" are separated by another red dot. Two light blue curved lines, resembling arcs or partial circles, are positioned around the first red dot: one starts above the "P" and ends below the "E", and the other starts below the "P" and ends above the "E".

PE SYSTEMS

Short Bio Kevin Hermanns

Co-Founder &
Managing Director



TECHNISCHE
UNIVERSITÄT
DARMSTADT

Research Engineer:
Distortions of High Power
Converters

Document & Configuration
Management for large scale
rail automation projects



Bachelor & Master Degree in
Electrical Engineering: Focus
Electrical Power Engineering



Kevin Hermanns

Born 1984 in Germany

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0049 6151 4924840



Founding Chair of Technical Committee
10 (Design Methodologies)



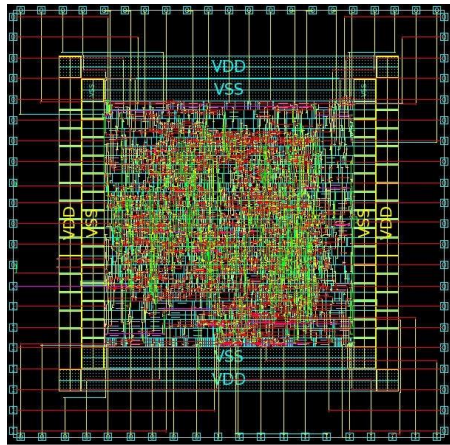
Member of TC47/SC47E/WG03 Power
Devices: Standards in scope IEC 60747-
2, -6, -7, -8, -9, -15



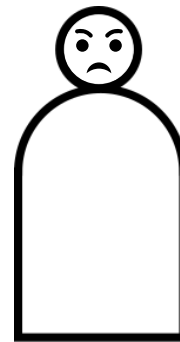
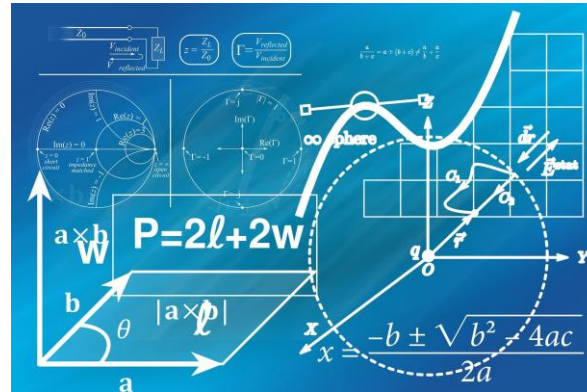
Contribution on Distortions for CLC/TS
50654: HVDC Grid Systems and
connected Converter Stations - Guideline
and Parameter Lists for Functional
Specifications

Growing Complexity

Integrated Circuits 1980's



Growing complexity mastered by Electronic Design Automation (EDA)



R&D and Design Engineer

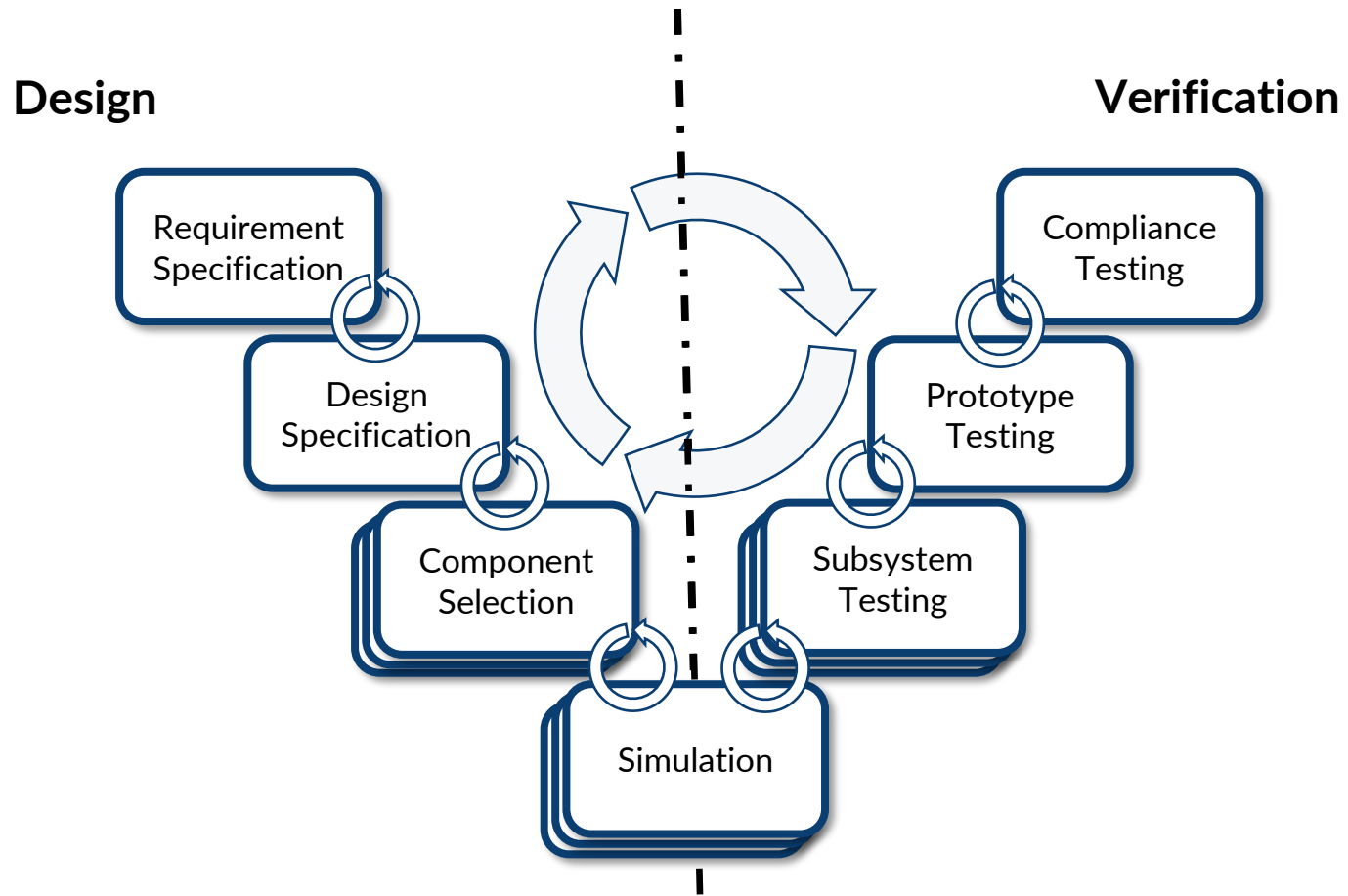
Power Electronics 2020's

Component data are not available in the required quantity and quality

Power Electronics Conversion system involves supply of multiple vendors

More degrees of freedom

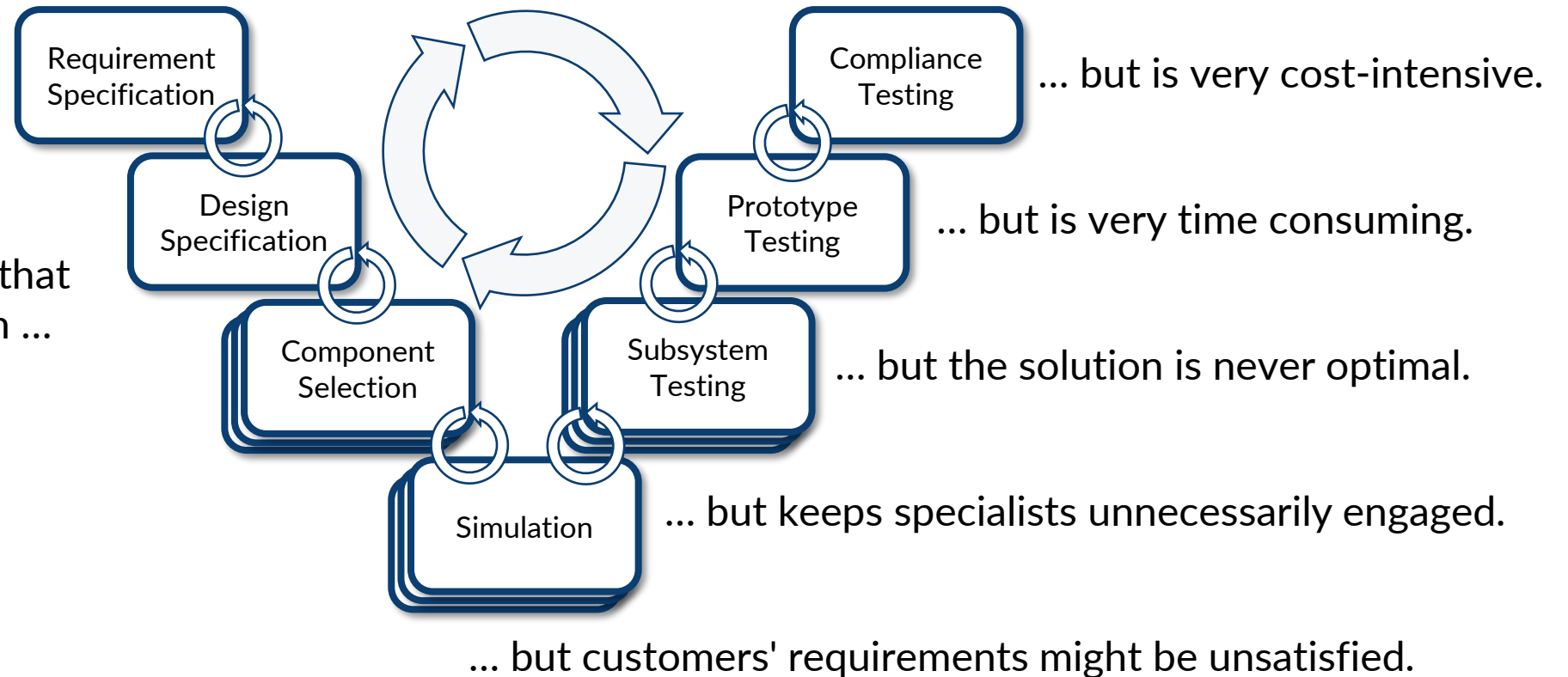
Power Electronics Design Process



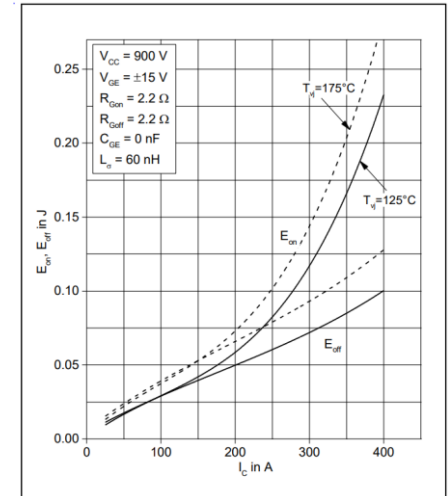
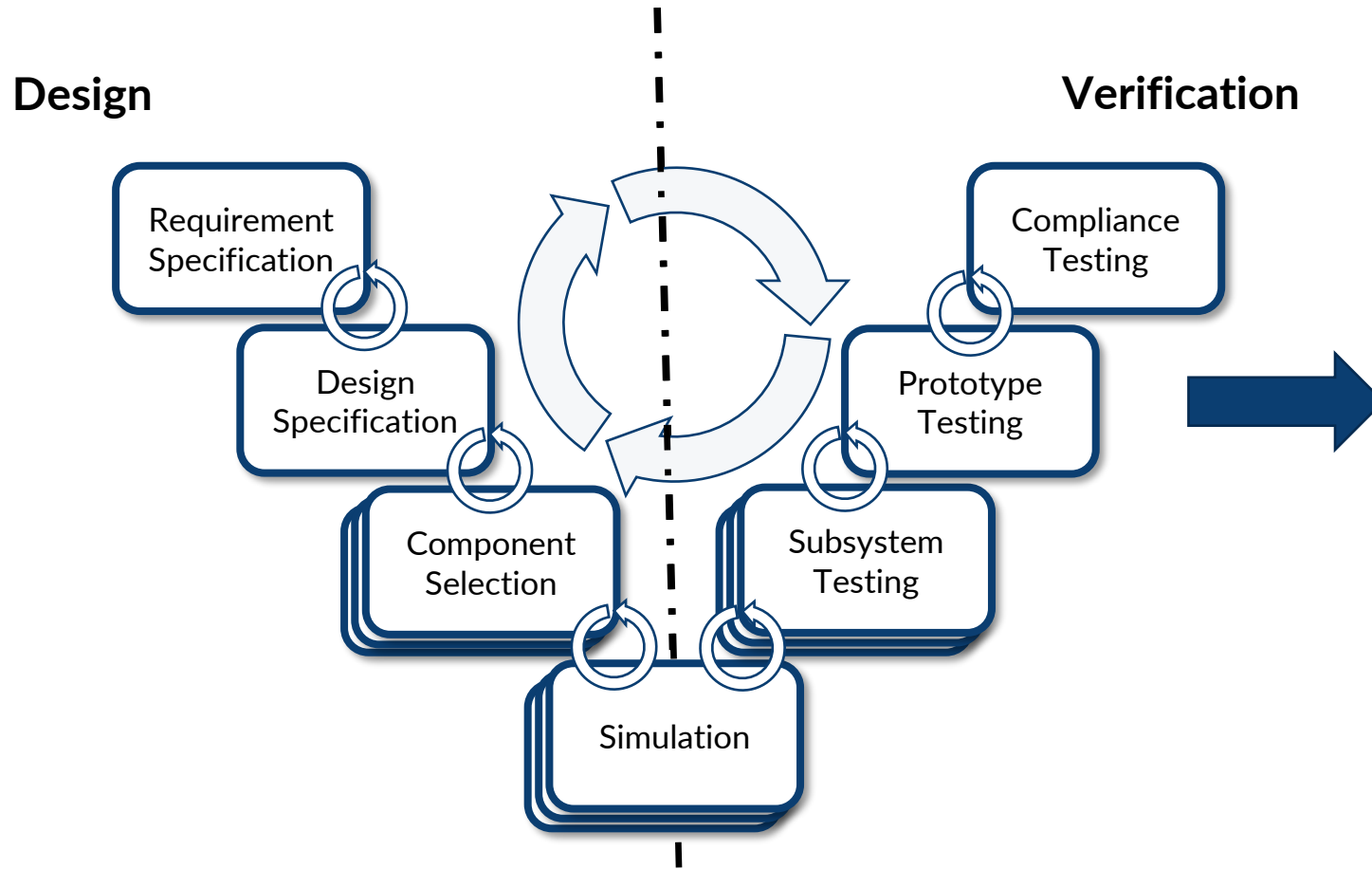
Where can double pulse test measurements help?

Current Power Electronics Design Process

Iterative design process, that always leads to a solution ...



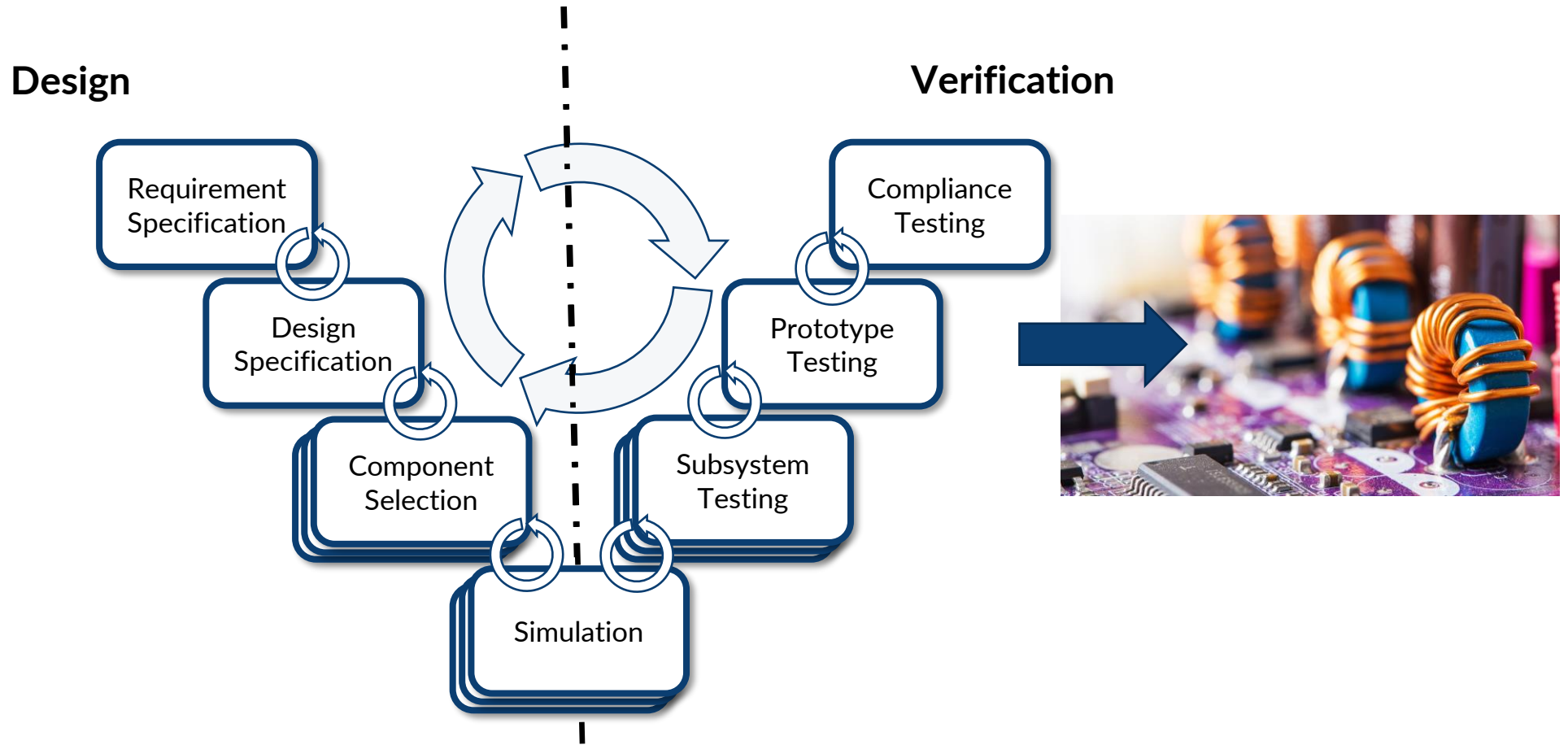
Device Vendor View



Data sheet creation

Where can double pulse test measurements help?

System Integrator View

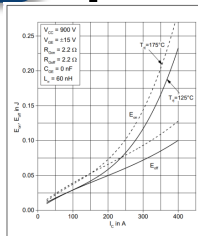
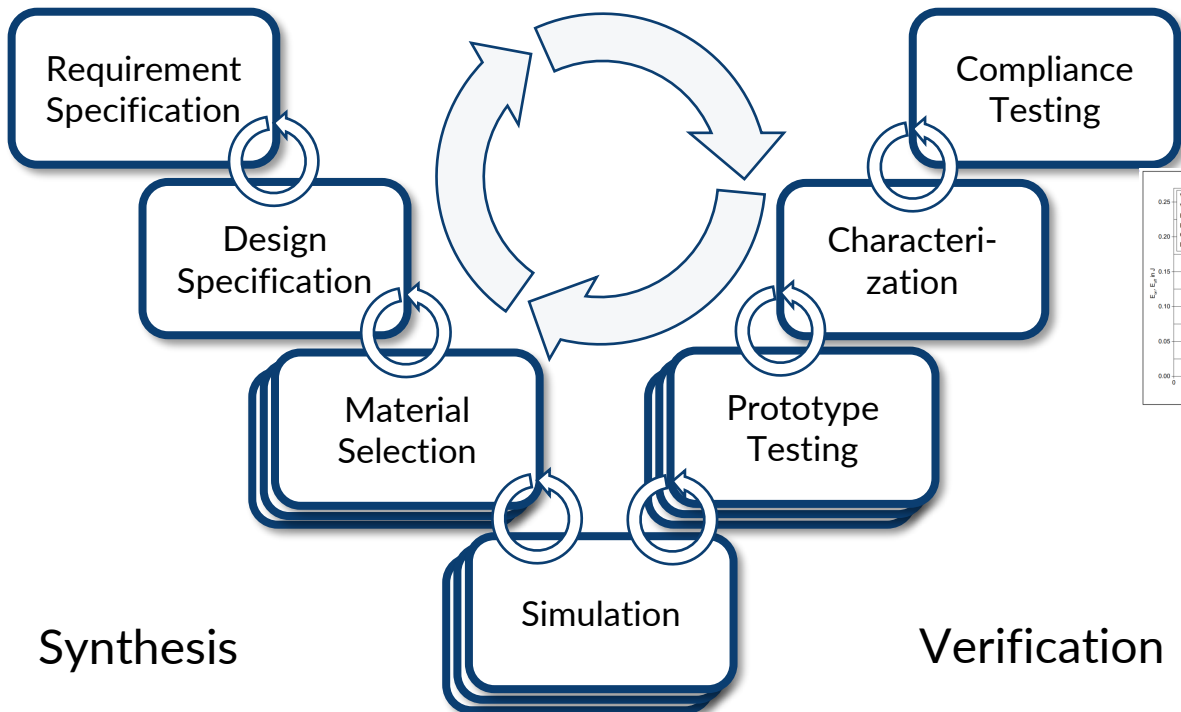


Where can double pulse test measurements help?

How do we get shorter time-to-market?

Two Un-linked Process Flows

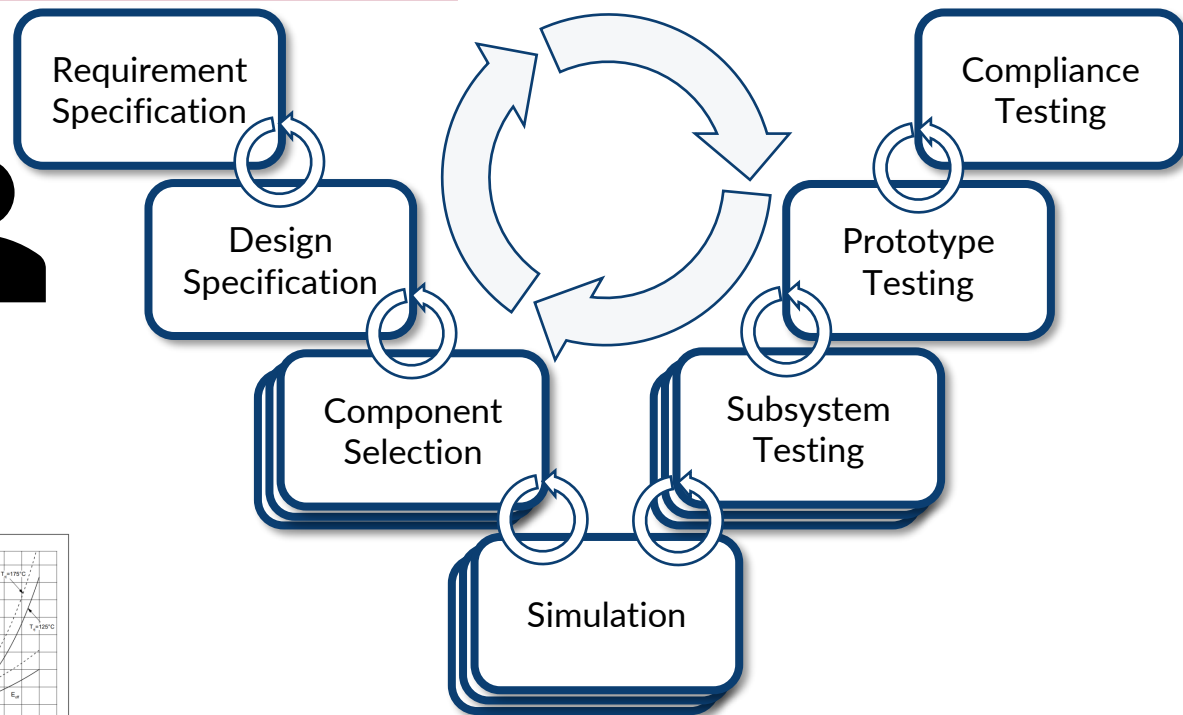
Component Design



Synthesis

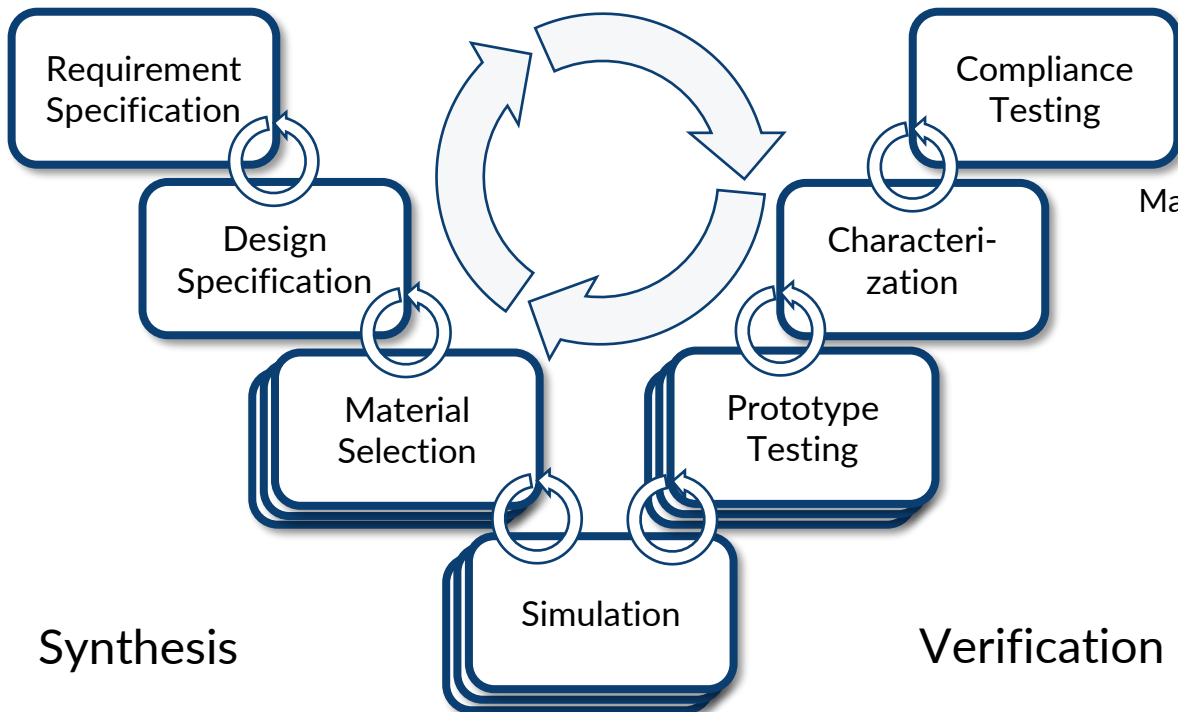
Verification

System Design



Design Automation

Component Design



Component Requirements

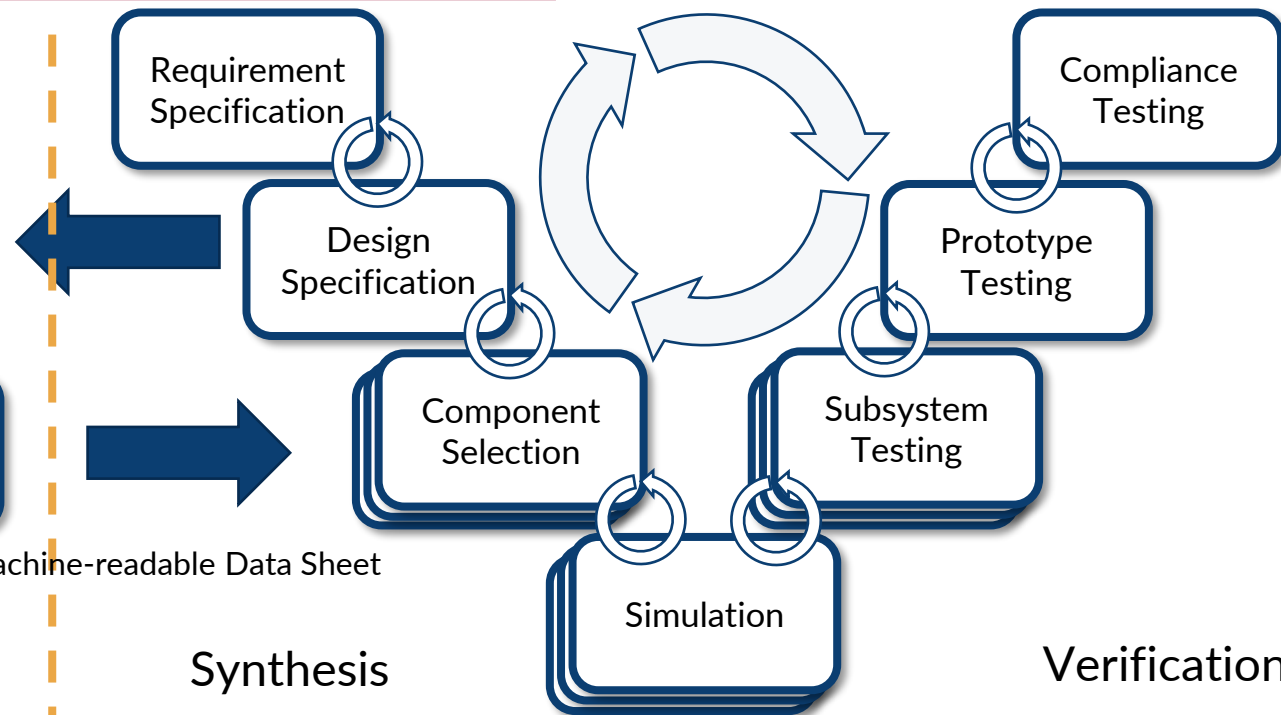
Machine-readable Data Sheet

Synthesis

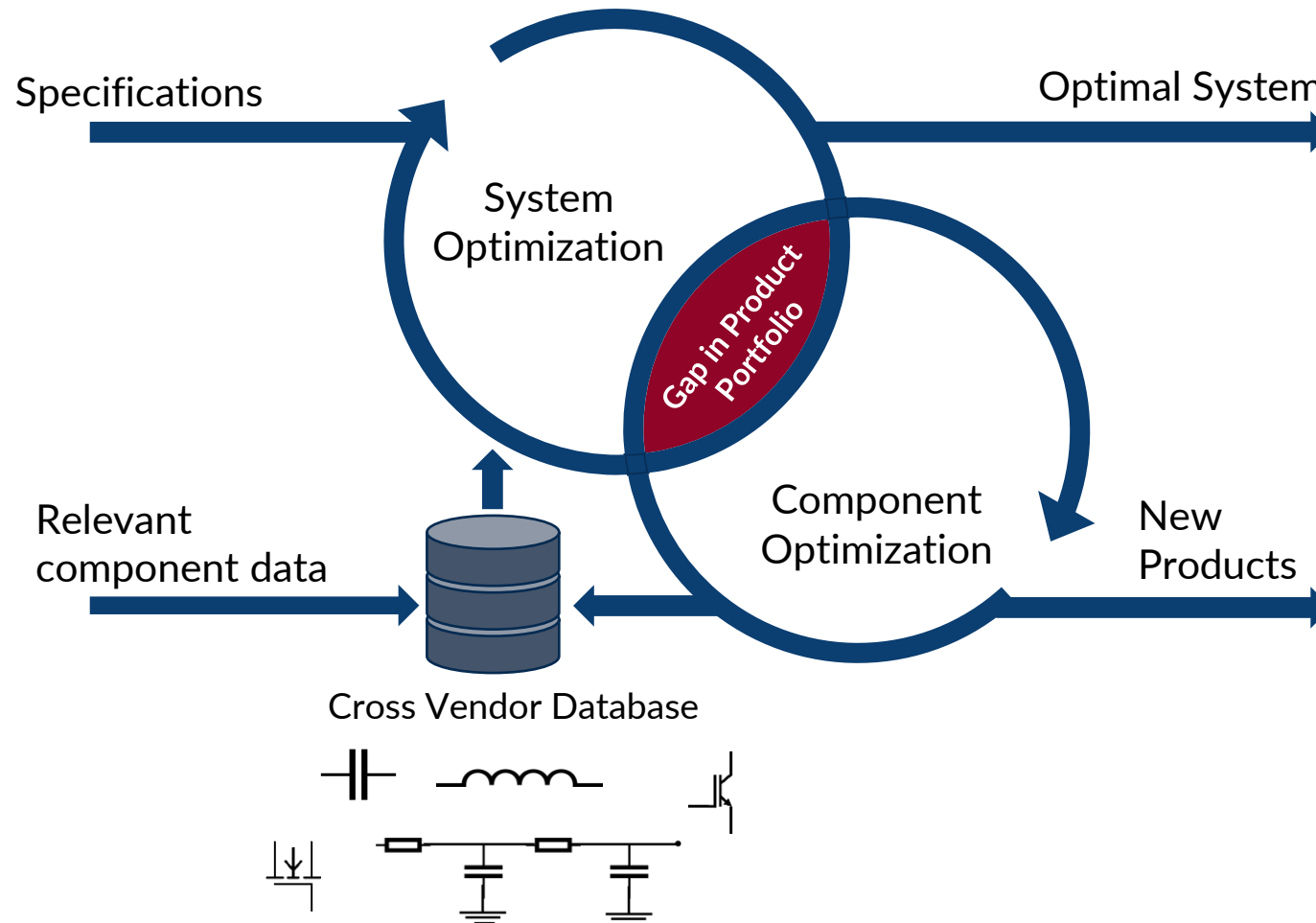
System Design

Verification

Verification

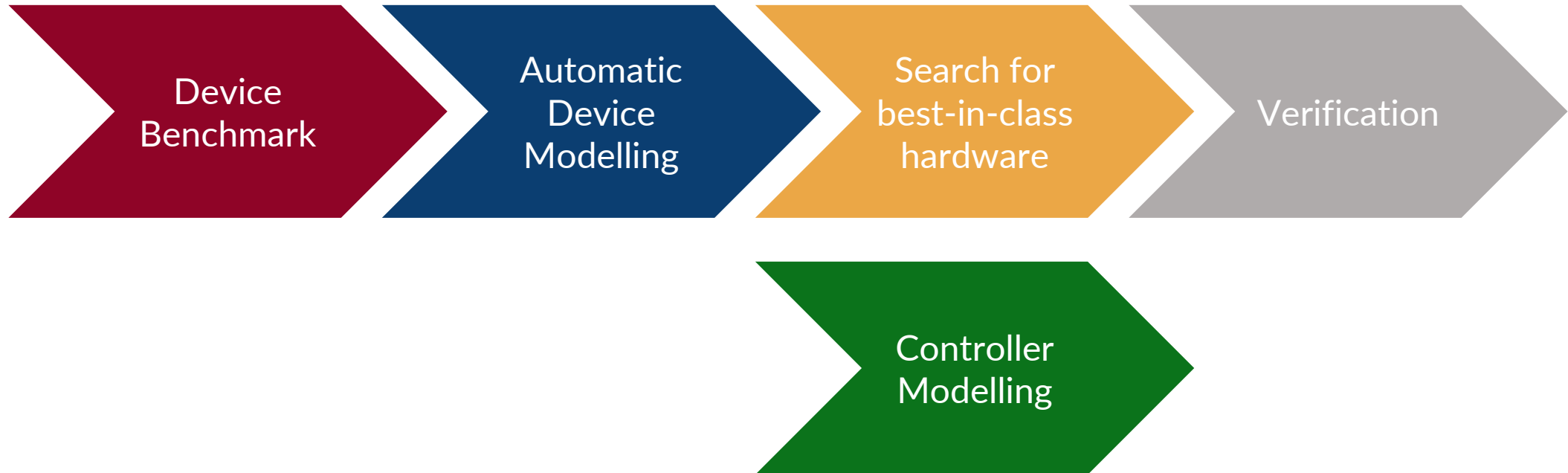


Design Automation is Collaborative




What can we do now?

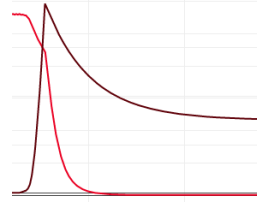
Shorter Design Flow



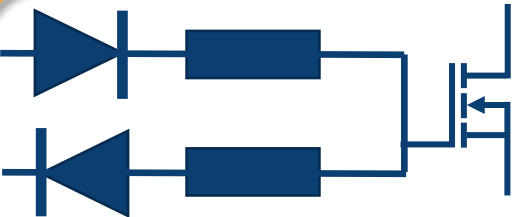
Use Cases



Device Benchmark & Component Selection



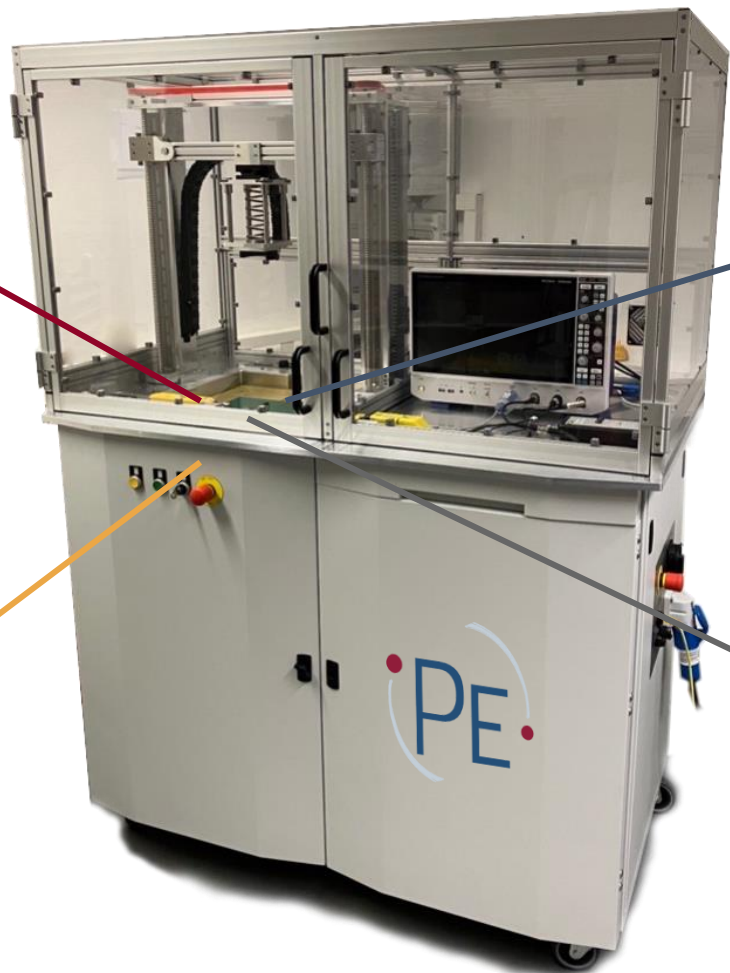
Automatic Model Generation



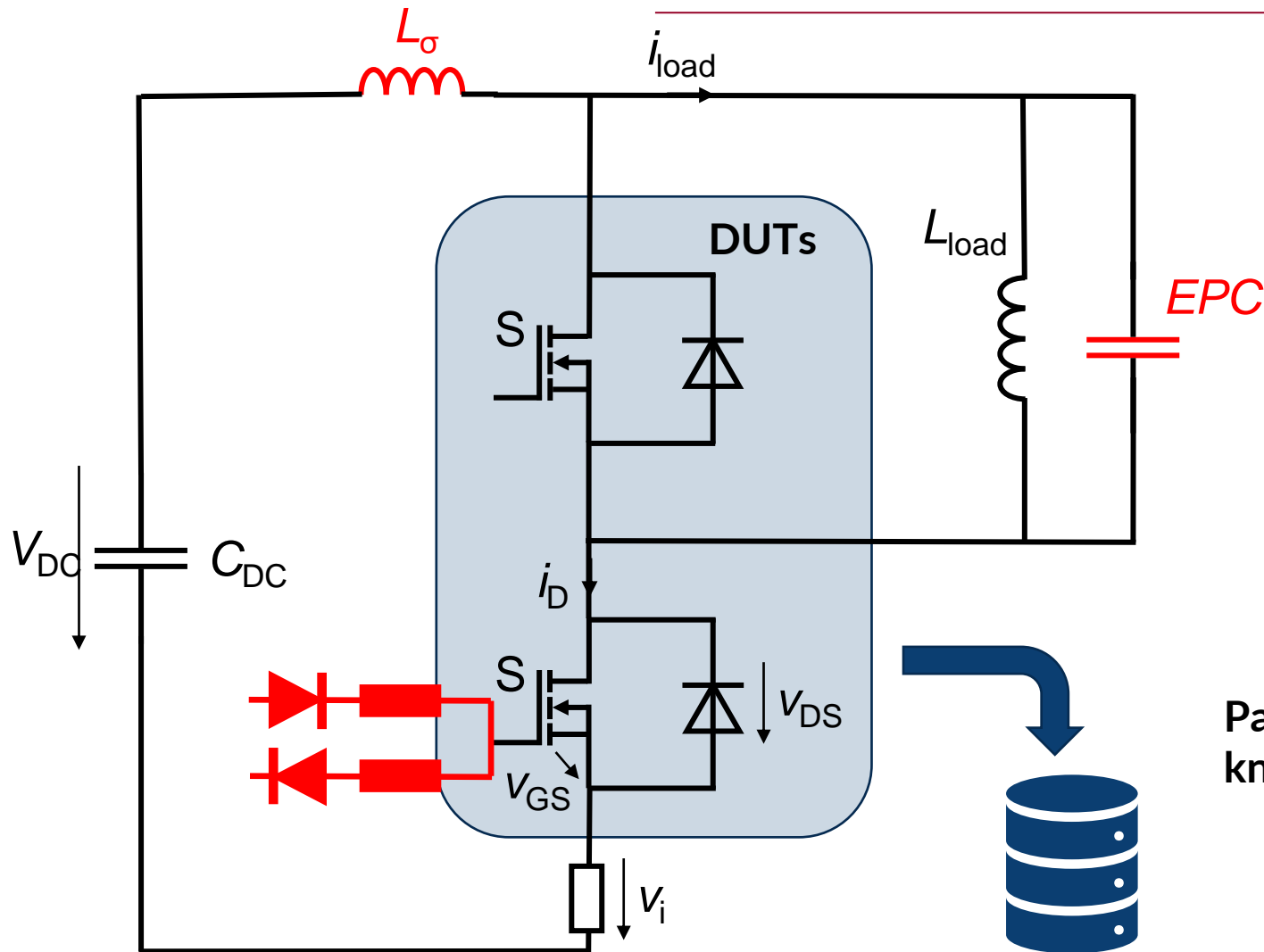
Search for Driver Settings



System Verification



Use Case - Benchmark

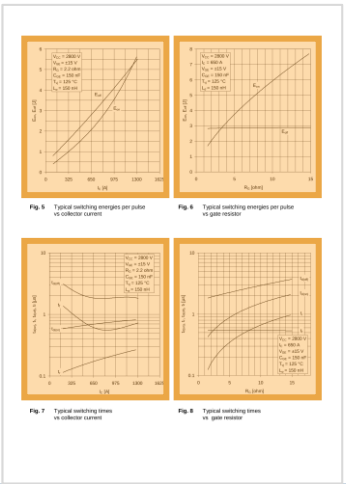
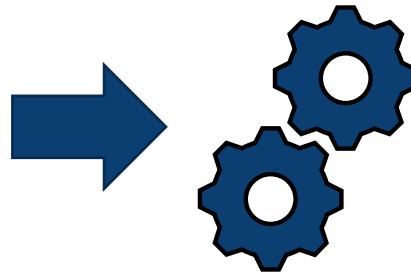
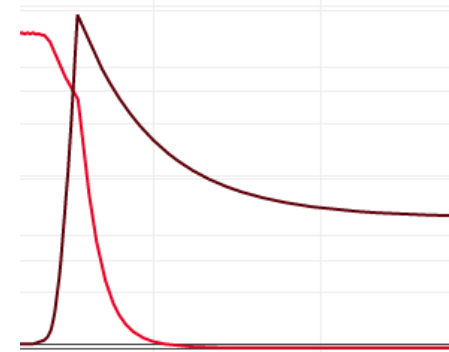


- Measurement environment well known
- De-embedding of imperfections results in “real” device performance
- Measurements are repeatably
- Comparison of different devices easy

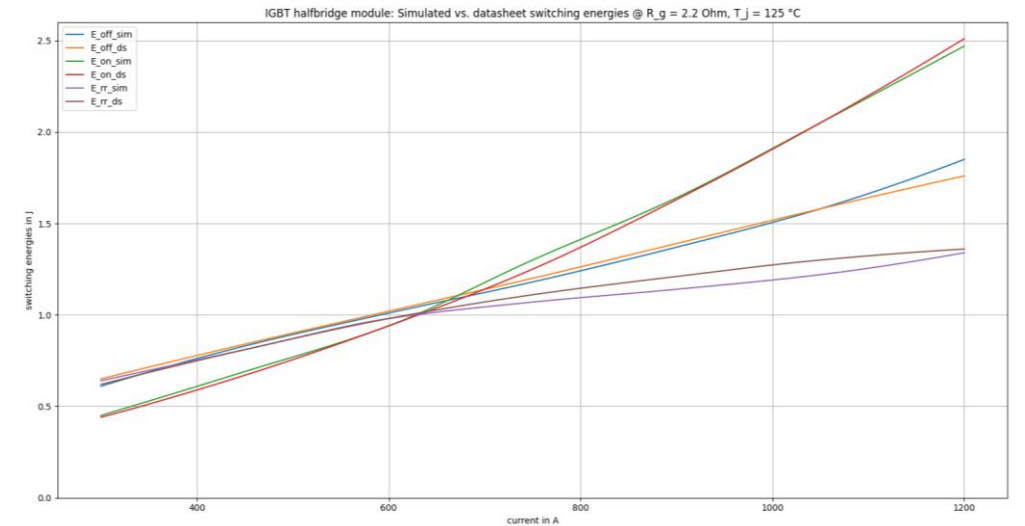
Parasitics of DPT must be well known and taken into account

Use Case – Model Generation

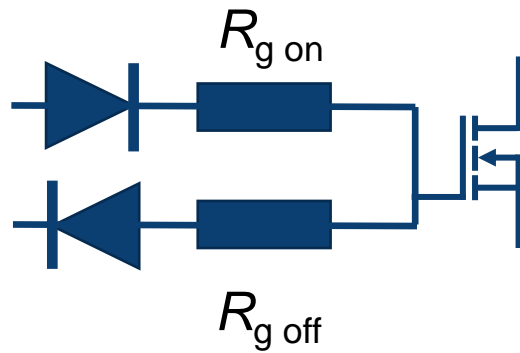
- Accurate measurements allow better device models
- Automatic generation possible
- Quality metrics can be developed and applied (accuracy information)



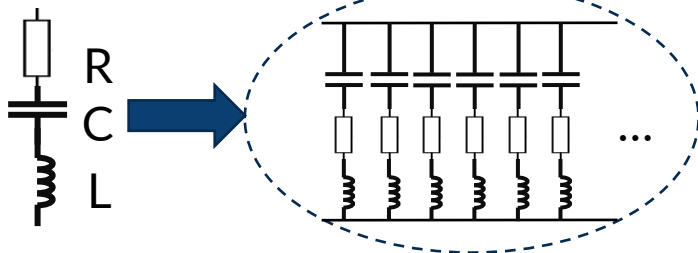
Static information can be obtained with DataSheetVision



Use Case – Search Best-in-class Hardware



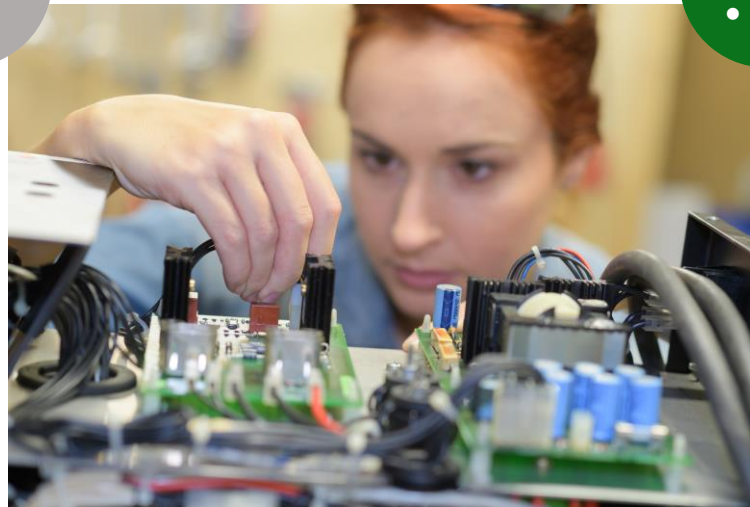
- For ideal DC-Link designer has various options
- Driver parameters are compromise with various options
- Contingency operations may require design margin
- For programmable gate drives parameter search automated



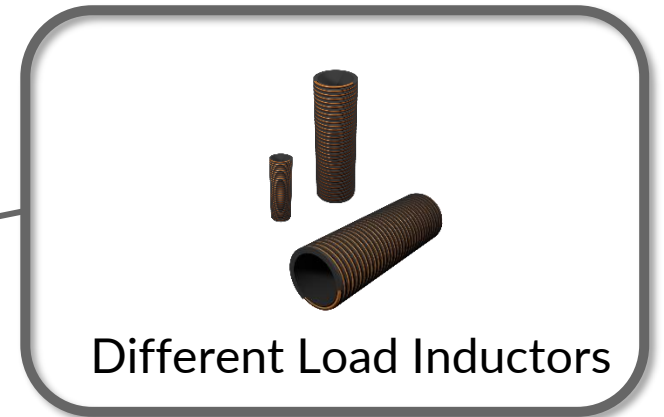
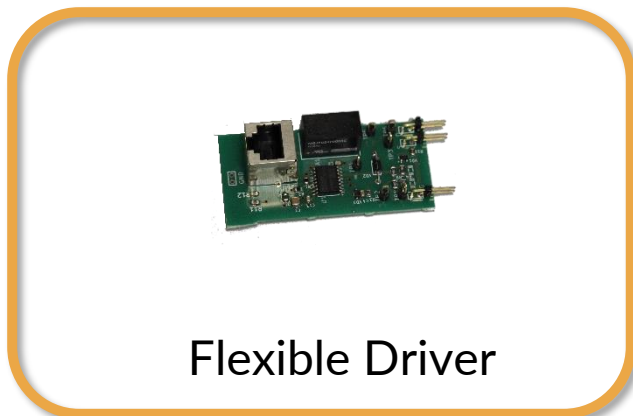
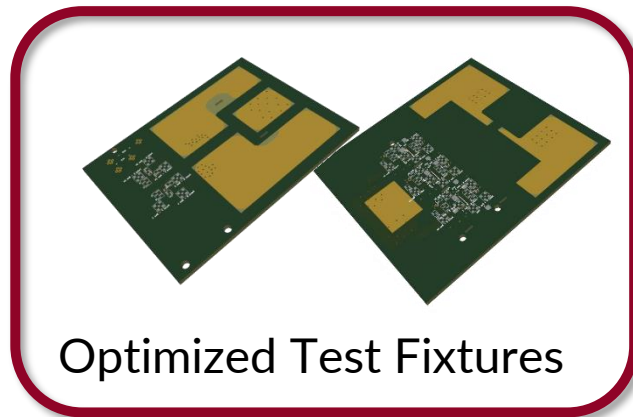
Use Case – Design Verification

- Measurements on real setup for verification purposes
- Allow further optimization but in the region of model uncertainty
- Close of “control loop” points out shortcomings in modelling
- Shortcomings can be addressed and models become better

- For design of controllers circuit simulations are quite simple (ideal switch and look-up table)
- The commonly used look-up tables described in XML files can be generated according to operation parameters
- Improved accuracy



Modularity



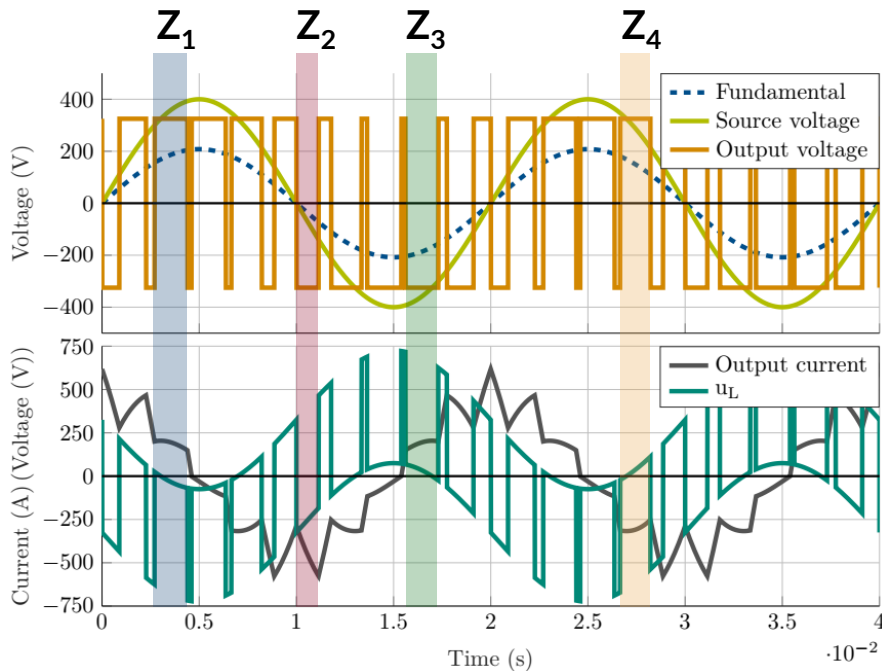
Modular Double-Pulse Tester

Testing Close to Application

- Allows testing with highly optimized characterization setups
- Allows testing of in-site device performance
- Accompanies systems development from first comparisons to system verification tests on prototypes.

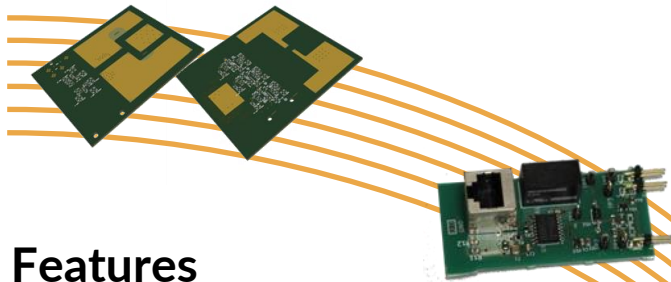
Benefits for the Lab Engineers

- Automatic parameter extraction
- Automatic de-skew
- Plausibility checks of measurement results
- Automatic model generation
- Ergonomic workbench



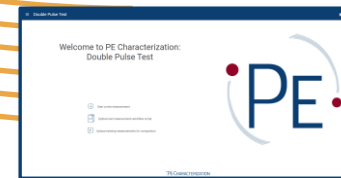
**Figure
e.g. 62 mm
module fixture**

Modular Double-Pulse Tester



Features

- Test voltage up to 2 kV (higher voltage on request)
- Test current up to 3.6 kA
- Test temperature -40 to 250 °C
- Optimized test fixtures for all packages
- Universal gate drivers
- Different load inductors and DC-links
- Very low stray inductance
- High performance scope and probes of multiple vendors or integration of pre-existing equipment



Benefits

- Modules, discretes, silicon, SiC and GaN – one tester for all devices
- Fast setup times
- Avoidance of human errors through error-detecting software
- Fast amortization due to reduction of required human resources
- Use of existing infrastructure (compatibility)

Be prepared for upcoming challenges!



DPT Solutions - Overview

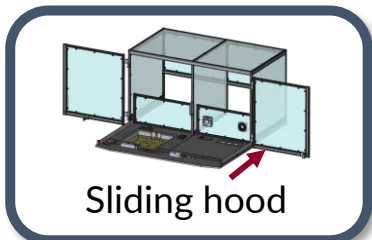


Base frame:

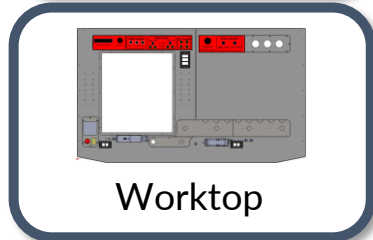
+ Additional Equipment



Base cabinet



Sliding hood



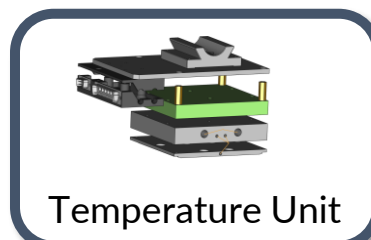
Worktop



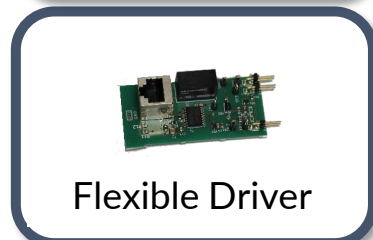
Safety Circuit



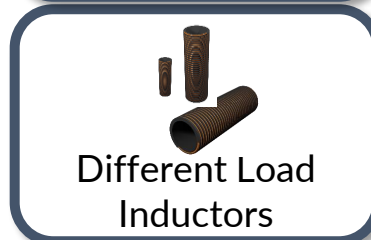
Contacting Unit



Temperature Unit



Flexible Driver



Different Load Inductors



High Voltage Source



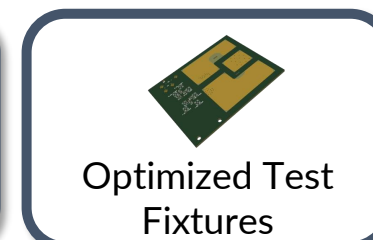
ThermoStream



DC Link



High-Performance Measurement Equipment



Optimized Test Fixtures



Laboratory Source

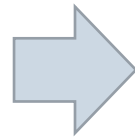
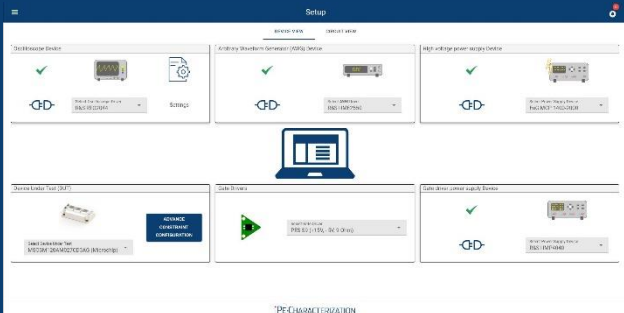


Automatization Software

Software is the Key

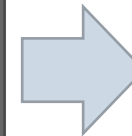
Setup Configuration

- Probe Selector
- Connection Manager
- Conflict Manager



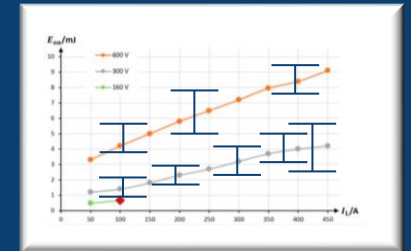
Conduction of Measurement

- Parameter sweeps
- Automatic de-skew
- Measurement campaign saving
- Plausibility checks



Post Processing

- Smoothing
- Parameter extraction (IEC standard)
- Error quantization
- Local Data management
- Interfaces ext. tools?



Conflict Manager – Human Error Reduction

Cross-checking of all user settings to prevent damage at DUT or measurement devices

Pre-processing:

- Voltage & current limit checks:
 - Sweep definition
 - Probe selection
- Signal generation (prevent overheating)
- Instrument settings
- ...

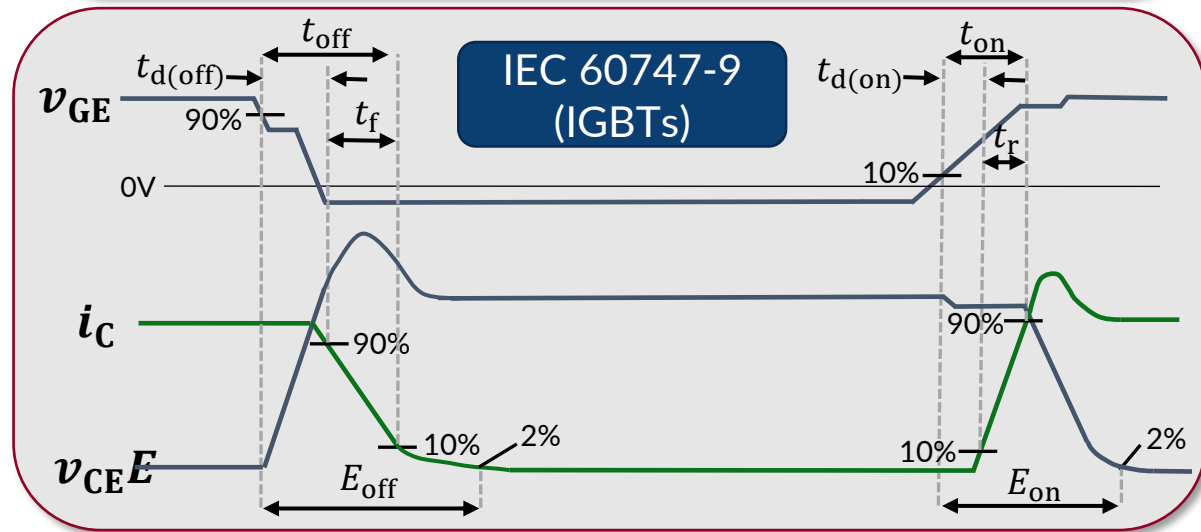
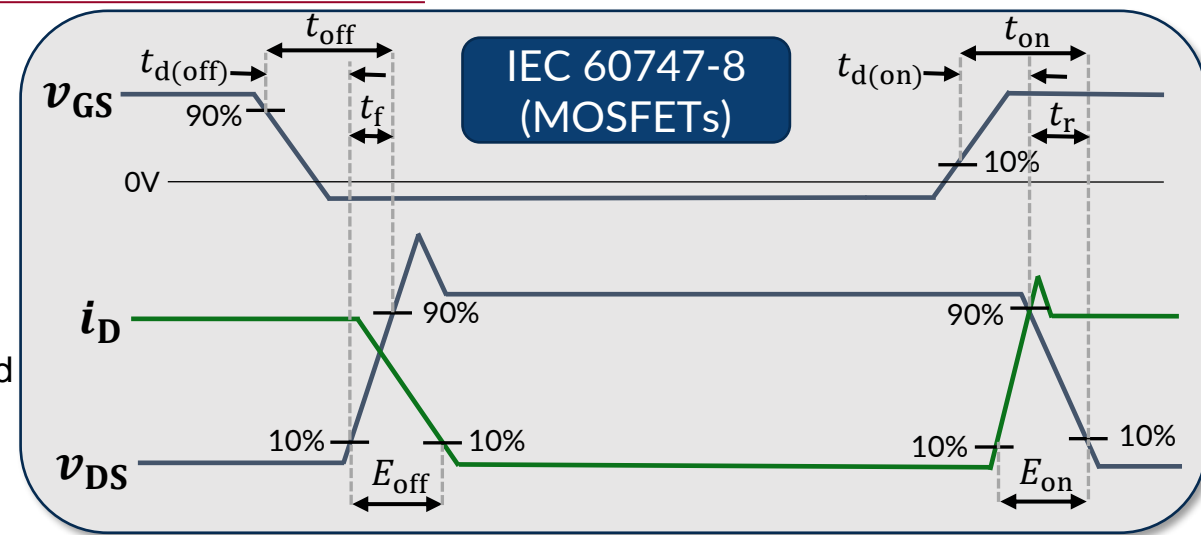
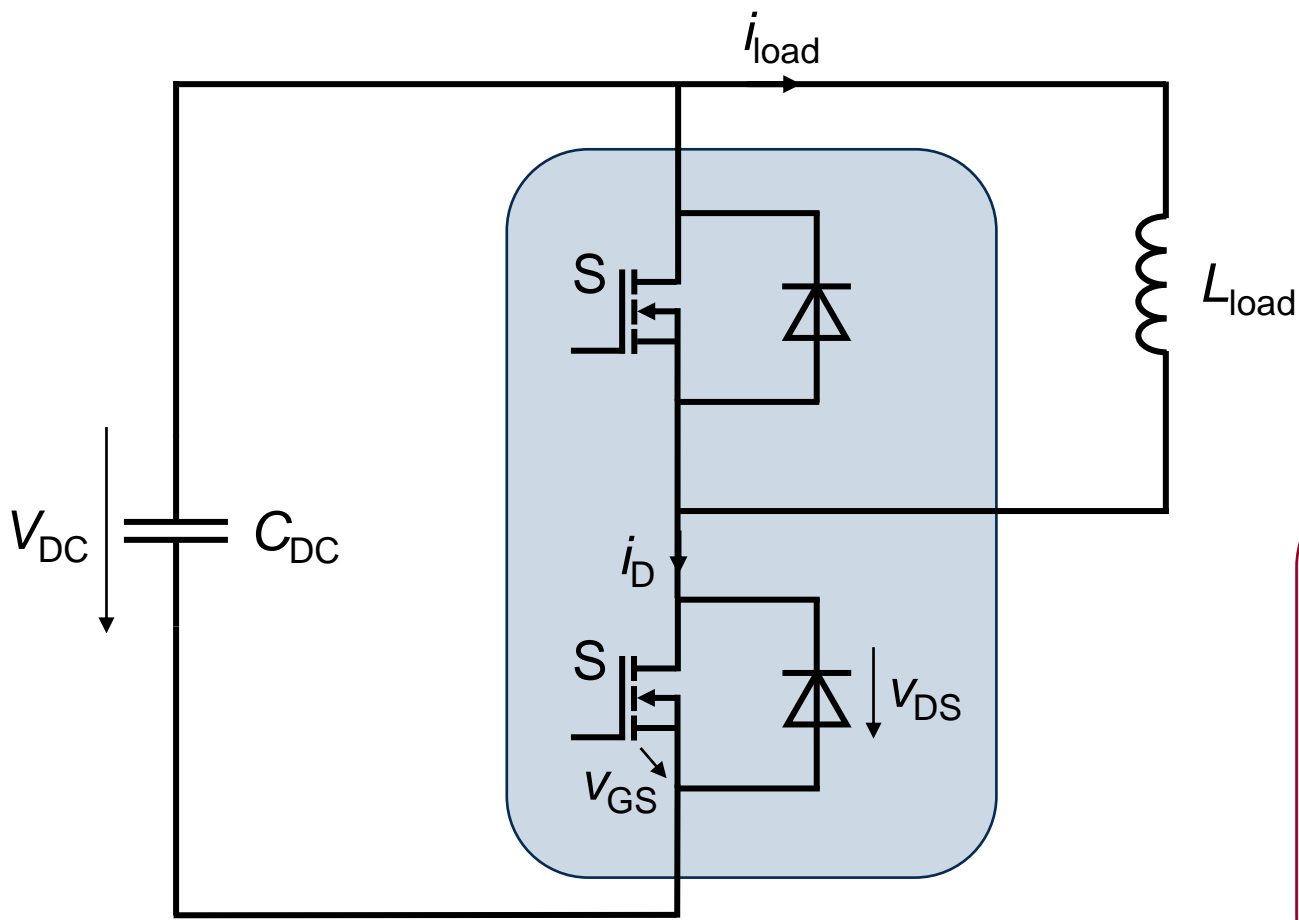
Conduction of Measurement:

- Connectivity checks
- Adjust instrument settings to operation point in case of clipping
- Signal plausibility checks for trigger faults
- ...

Post-processing:

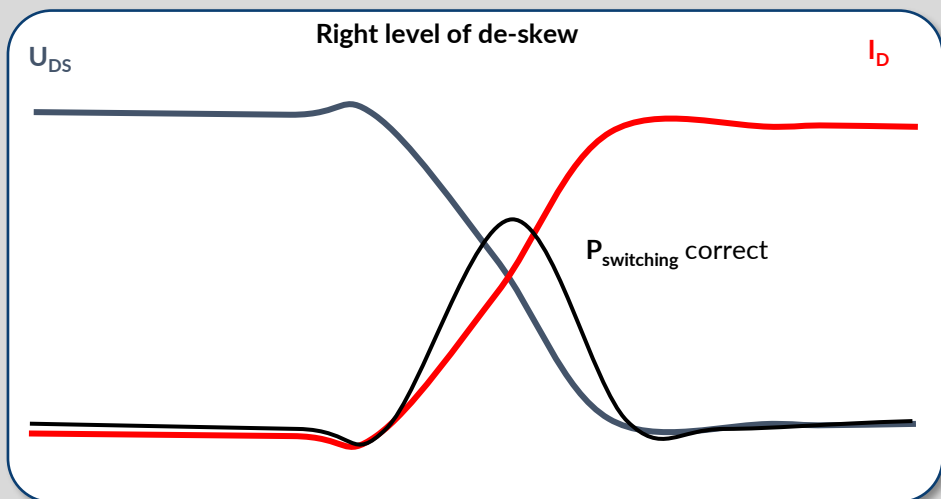
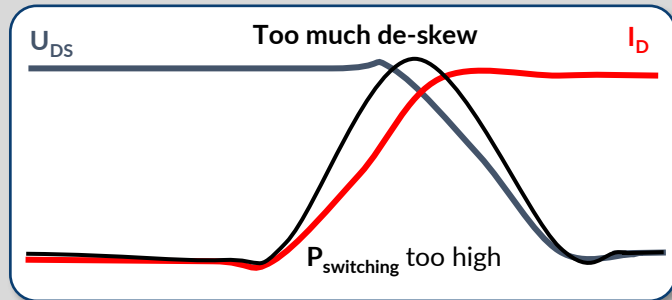
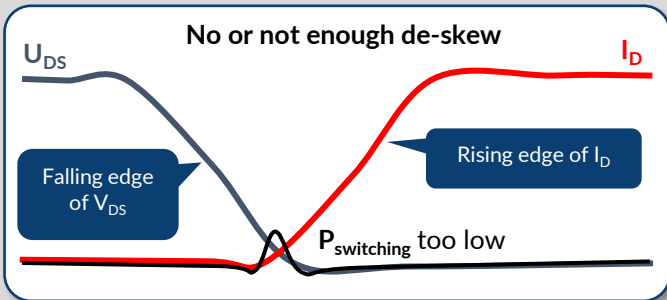
- Plausibility checks for extracted parameters
- Noise filtering
- De-skew
- Error quantification (error calculation package)
- Statistical evaluation (math package)
- ...

Testing of Inductive Switching - Standard

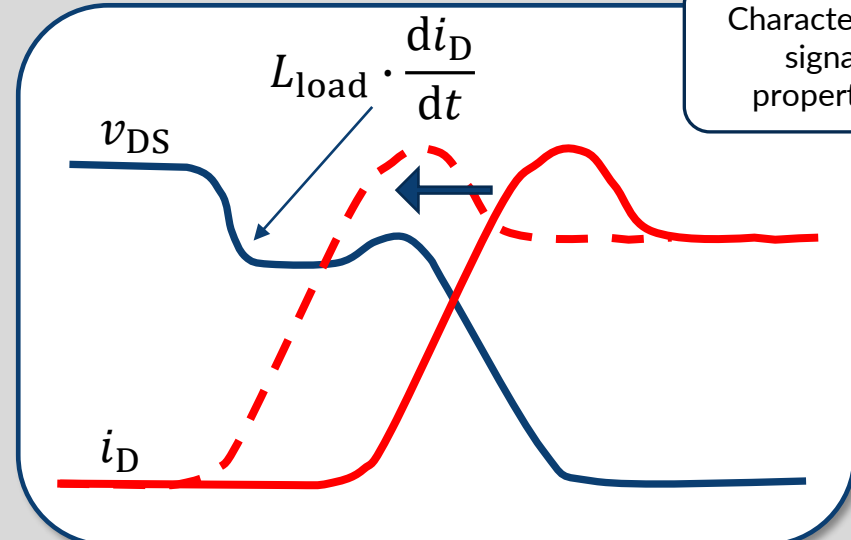


Automatic De-Skew

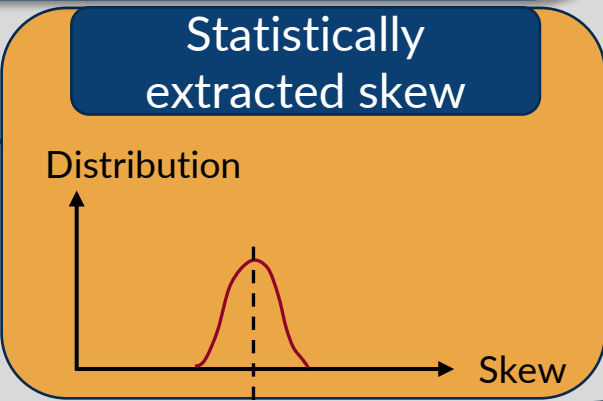
De-skew issue



Automatic de-skew



Calculated for each signal



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